

Referenčna oznaka	Naslov
8B/42/NP	PNW TS 8B-42: Guideline for the hosting capacity evaluation of distribution networks for distributed generations
8B/43/NP	PNW 8B-43: Test requirements for the functional simulation of DER integration
17C/719/NP	PNW 17C-719: AC metal enclosed busbar trunking systems (BTS) including solid and air insulated design for rated voltages above 1 kV and up to and including 52 kV
22E/200/NP	PNW 22E-200: Bi-directional grid connected power converters, Part 3: EMC requirements and test methods
22F/541/NP	PNW 22F-541: Future IEC 60700-3 Ed.1.0: Thyristor valves for high voltage direct current (HVDC) power transmission - Part 3: Essential ratings (limiting values) and characteristics
22H/249/NP	PNW 22H-249: Power Converter Sub-System (PCSS) for use in Electrical Energy Storage Systems (EESS) - Method of specifying the performance and test requirements
32C/572/NP	PNW 32C-572: Technical requirements for organic-temperature-sensing thermal-links
37A/339/NP	PNW 37A-339 ED1: Surge protective devices connected to low-voltage DC power systems - Requirements and test methods
46F/478/NP	PNW 46F-478: RADIO-FREQUENCY CONNECTORS – Part 21: sectional specification for RF coaxial connectors with inner diameter of outer conductor 9,5 mm (0,374 in) with screw coupling — Characteristic impedance 50 ohms (Type SC)
46F/479/NP	PNW 46F-479: RADIO-FREQUENCY CONNECTORS –Part 1-X: Electrical test methods- RF power
46F/482/NP	PNW 46F-482: Multi radio frequency channel connector Part 3: Sectional specification for MQ5 series circular connector
47/2576A/NP	PNW 47-2576: Semiconductor devices - Reliability test method for silicon carbide discrete metal-oxide semiconductor field effect transistors - Part 1: Test method for bias temperature instability
47/2577A/NP	PNW 47-2577: Semiconductor devices - Reliability test method for silicon carbide discrete metal-oxide semiconductor field effect transistors - Part 2: Test method for bipolar degradation by body diode operating
47E/670/NP	PNW 47E-670: Semiconductor devices – Part 16-7: Microwave integrated circuits – Attenuators
47E/671/NP	PNW 47E-671: Semiconductor devices – Part 16-8: Microwave integrated circuits – Limiters
47F/340/NP	PNW 47F-340: Semiconductor devices - Micro-electromechanical devices - Part 39:Terms and definitions of Micro-electromechanical inertial shock switch
47F/341/NP	PNW 47F-341: Semiconductor devices - Micro-electromechanical devices - Part 40:Test methods of Micro-electromechanical inertial shock switch threshold

57/2125/NP	PNW 57-2125: Framework for energy market communications - Part 451-8: HVDC processes, contextual and assembly models for European style market
62A/1343/NP	PNW TS 62A-1343: Health software - Part 2: Health and wellness apps - Quality criteria across the life cycle - Code of practice
64/2388/NP	PNW TS 64-2388: Application guides complying with IEC 60364 - Asynchronous motor starting and protection
64/2389/NP	PNW TS 64-2389: Application guides complying with IEC 60364 - Lighting circuits
64/2390/NP	PNW TS 64-2390: Application guides complying with IEC 60364 - Uninterruptible Power Systems
64/2391/NP	PNW TS 64-2391: Application guides complying with IEC 60364 - Rotating generators
64/2392/NP	PNW TS 64-2392: Application guides complying with IEC 60364 - Source changeover system
65C/974/NP	PNW 65C-974: Industrial communication networks - Fieldbus specifications and Profiles - Type 28 elements and CPF 22 (AUTBUS)
65E/659/NP	PNW 65E-659: Industrial automation equipment and systems - Predictive maintenance
65E/661/NP	PNW 65E-661: Engineering data exchange format for use in industrial automation systems engineering - Automation Markup Language - Part 5: Communication
80/933/NP	PNW 80-933: <p>Maritime survivor locating systems and devices (Man overboard systems), minimum requirements, methods of test and required results - Part 1: General requirements and aspects applicable to MOB devices</p>
80/934/NP	PNW 80-934: <p>Maritime survivor locating systems and devices (man overboard systems), minimum requirements, methods of test and required results - Part 2: AIS functionality of man overboard device - Operational and performance requirements, methods of testing and required test results</p>
80/935/NP	PNW 80-935: <p>Maritime survivor locating systems and devices (man overboard systems), minimum requirements, methods of test and required results - Part 3: DSC functionality of man overboard device - Operational and performance requirements, methods of testing and required test results</p>
86C/1610/NP	PNW 86C-1610: Fibre optic sensors – Part 5-1: Tilt measurement – Tilt sensors based on fibre Bragg gratings
91/1590/NP	PNW 91-1590: MATERIALS FOR PRINTED BOARDS AND OTHER INTERCONNECTING STRUCTURES – Part 6-11: Sectional specification set for reinforcement materials – Specification for finished fabric woven from “Low Dk” glass for printed boards

91/1593/NP	PNW 91-1593: Test methods for electrical materials, printed board and other interconnection structures and assemblies – Part 2-XXX: Test methods for materials for interconnection structures – Decomposition Temperature (Td) using TGA
91/1594/NP	PNW 91-1594: Test methods for electrical materials, printed board and other interconnection structures and assemblies – Part 2-X: Test methods for materials for interconnection structures–Measurement of Resilience strength and Resilience strength Retention Factor of Flexible Dielectric Materials
110/1116/NP	PNW 110-1116: Laser displays - Part 5-7: Measuring methods of visual quality for scanning laser displays
110/1120/NP	PNW 110-1120: Eyewear display – Part 22-20: Measurement methods for AR type – image quality
113/497/NP	PNW TS 113-497: Nanomanufacturing - Key control characteristics - Part 6-12: Graphene film – Number of layers: Raman spectroscopy, optical reflection
SyCAAL/146/NP	PNW TS SYCAAL-146: (SRD) Design Considerations for AAL users in Connected Home Environment
SyCSmartCities/100/NP	PNW TS SYCSMARTCITIES-100: Systems Reference Deliverable - Use Case Collection and analysis: City Information Modeling for Smart Cities
JTC1-SC25/2894/NP	PNW TS JTC1-SC25-2894: Information technology – Generic cabling for customer premises – Part 9903: Matrix modelling of channels and links